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Application/Control No.	Applicant(s)/Patent under Reexamination	_
09/943,780	BAKER ET AL.	
Examiner	Art Unit	_
David J. Blanchard	1643	

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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
SEQ IC	0 NO:69	1/25/2007	DB B

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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updated search See attacked)	8/2/07	83
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